

June 2011

# FDB86135

# N-Channel PowerTrench<sup>®</sup> MOSFET 100V, 176A, 3.5m $\Omega$

#### **Features**

- Max  $P_{DS(on)} = 3.5 \text{m}\Omega$  at  $V_{GS} = 10 \text{V}$ ,  $I_D = 75 \text{A}$
- Fast Switching Speed
- · Low Gate Charge
- High Performance Trench Technology for Extremely Low  $R_{\mbox{\scriptsize DS}(\mbox{\scriptsize on})}$
- · High Power and Current Handling Capability
- RoHS Compliant

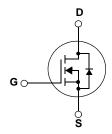
# **General Description**

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

# **Applications**

- · DC-DC primary bridge
- · DC-DC Synchronous rectification
- Hot swap





# **MOSFET Maximum Ratings** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter			Ratings	Units	
$V_{DSS}$	Drain to Source V	oltage			100	V
$V_{GSS}$	Gate to Source Vo	oltage			±20	V
	Drain Curren	- Continuo	ous (Silicon Limited)	$T_{\rm C} = 25^{\rm o}{\rm C}$	176	
I <sub>D</sub>	- Continuous( Package Limited)			ed) $T_C = 25^{\circ}C$	120	А
	- Continuous			$T_C = 25^{\circ}C(Note 1a)$	75	
	- Pulsed				704	Α
E <sub>AS</sub>	Single Pulsed Ava	alanche Energy		(Note 3)	658	mJ
Б	Dawer Dissination		$- T_C = 25^{\circ}C$	(Note 1a)	227	W
$P_{D}$	Power Dissipation - T <sub>A</sub> = 25°C		$- T_A = 25^{\circ}C$	(Note 1b)	2.4	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Sto	orage Temperat	ure Range		-55 to +175	°C

## **Thermal Characteristics**

Symbol	Parameter	Ratings	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case (Note 1)	0.66	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	62.5	C/VV

# **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDB86135	FDB86135	D2-PAK	330mm	24mm	800

# **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Charac	eteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V, T_C = 25^{\circ} C$	100	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, Referenced to 25°C	-	0.07	-	V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 80V, V_{GS} = 0V$	-	-	1	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	±100	nA

#### **On Characteristics**

$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2.0	•	4.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 75A$	-	3.0	3.5	mΩ
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 10V, I_D = 75A$	-	167	•	S

### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 05V V 0V	-	5485	7295	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 25V, V_{GS} = 0V$ 	-	2430	3230	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1101112	-	210	-	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V		-	89	116	nC
$Q_{gs}$	Gate to Source Gate Charge	$V_{DS} = 80V, I_{D} = 75A$ $V_{GS} = 10V$	-	24	-	nC
Q <sub>gs2</sub>	Gate Charge Threshold to Plateau	V <sub>GS</sub> = 10V	-	8	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge		-	25	-	nC

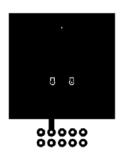
# **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time	50// 754	-	22	54	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 50V, I_D = 75A$	-	54	118	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 10V, R_{GEN} = 4.7\Omega$	-	37	84	ns
t <sub>f</sub>	Turn-Off Fall Time		-	11	32	ns

#### **Drain-Source Diode Characteristics**

$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS} = 0V, I_{SD} = 75A$ (Note 2)	-	-	1.25	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0V$ , $I_{SD} = 75A$ , $V_{DD} = 80V$	-	72	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$	-	129	-	nC

1. R<sub>0,1A</sub> is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0,1C</sub> is guaranteed by design while R<sub>0,1C</sub> is determined by the user's board design.



a) 40 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper



b) 62.5 °C/W when mounted on a minimum pad of 2 oz copper

- 2. Pulse Test: Pulse Width < 300  $\mu$ s, Duty cycle < 2.0 %. 3. Starting T  $_J$  = 25 °C,  $\,$  L = 1 mH, I  $_{AS}$  = 36.3 A, V  $_{DD}$  = 100 V, V  $_{GS}$  = 10 V.

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

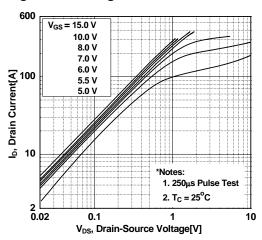


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

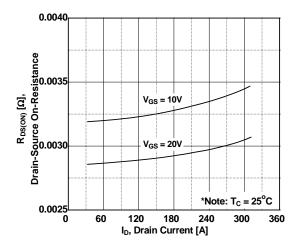


Figure 5. Capacitance Characteristics

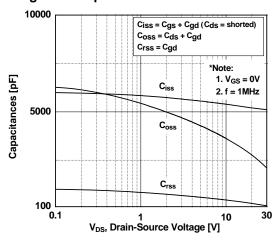


Figure 2. Transfer Characteristics

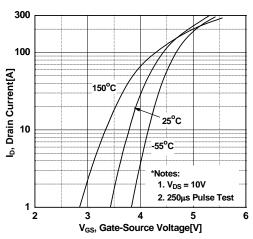


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

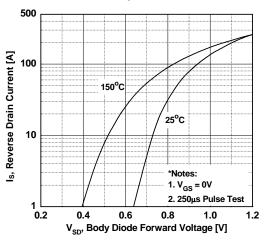
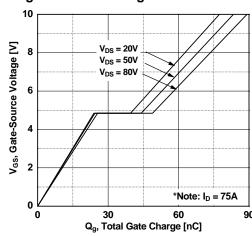


Figure 6. Gate Charge Characteristics



# **Typical Performance Characteristics**

Figure 7. Breakdown Voltage Variation vs. Temperature

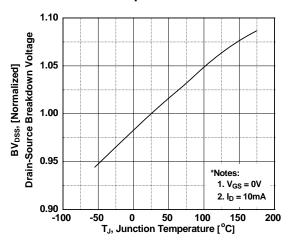


Figure 9. Maximum Safe Operating Area

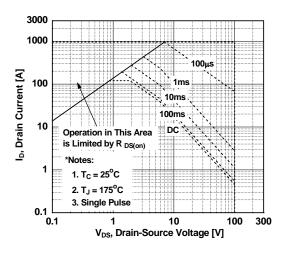


Figure 8. On-Resistance Variation vs. Temperature

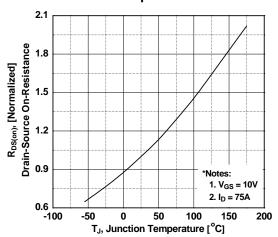


Figure 10. Maximum Drain Current vs. Case Temperature

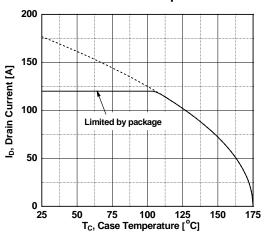
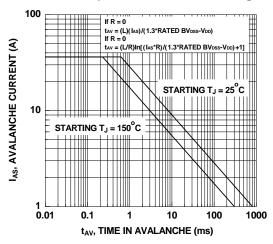
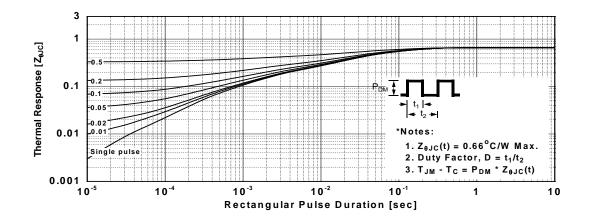


Figure 11. Unclamped Inductive Switching Capability

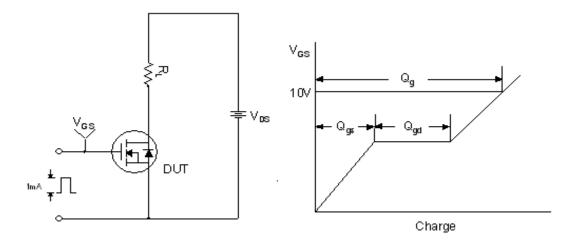


# **Typical Performance Characteristics**

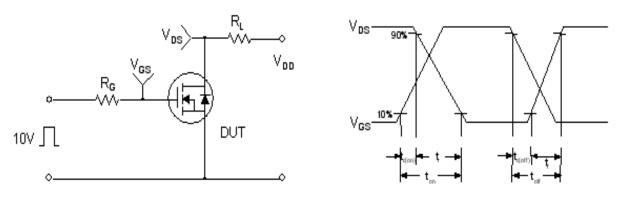
Figure 12. Transient Thermal Response Curve



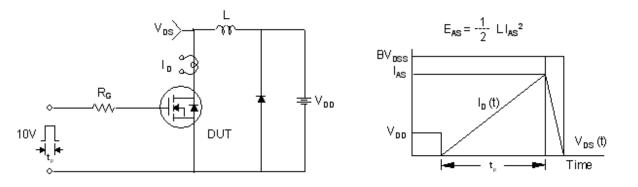
### **Gate Charge Test Circuit & Waveform**



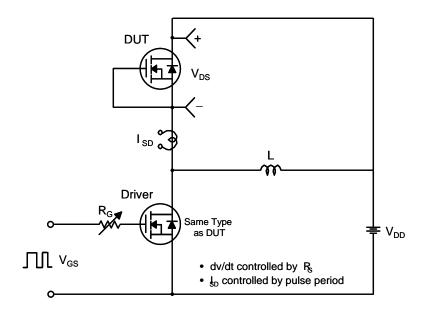
### **Resistive Switching Test Circuit & Waveforms**

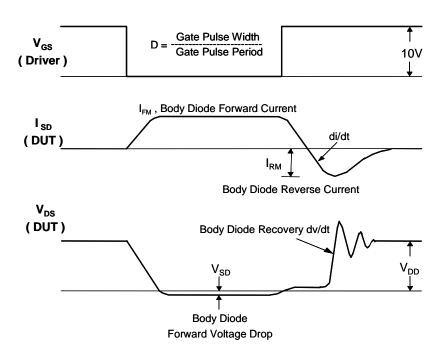


### **Unclamped Inductive Switching Test Circuit & Waveforms**



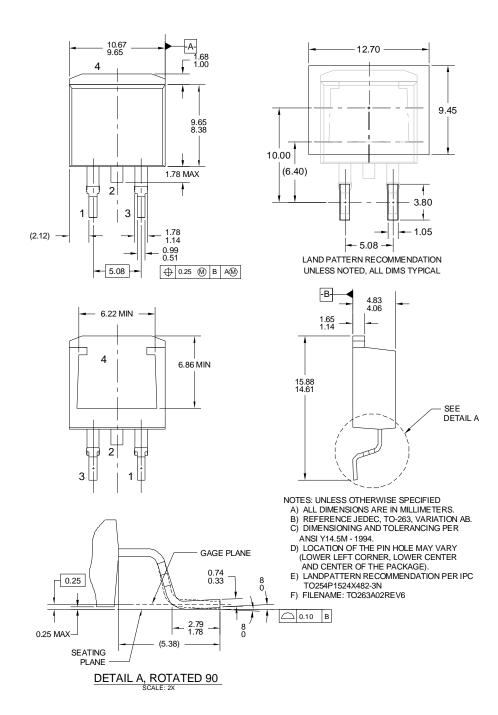
#### Peak Diode Recovery dv/dt Test Circuit & Waveforms





## **Mechanical Dimensions**

# D2-PAK



Dimensions in Millimeters





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